

Effects of environmental conditions on the performance of thermal imagers

Vendt, Riho; Juurma, Madis; Vabson, Viktor; Jaanson, Priit; **Kübarsepp, Toomas**; Noorma, Mart International journal of thermophysics 2011 / 1/2, p. 248-257 : ill <https://link.springer.com/article/10.1007/s10765-010-0896-4>

Feature article: Firmware updating systems for nanosatellites

Sünter, Indrek; Slavinskis, Andris; Kvell, Urmas; **Vahter, Andres**; Kuuste, Henri; Noorma, Mart; Kutt, Johan; Vendt, Riho; Tarbe, Karl; Pajusalu, Mihkel; Veske, Mihkel; Ilves, Taavi IEEE Aerospace and Electronic Systems Magazine 2016 / p. 36 - 44
<https://doi.org/10.1109/MAES.2016.150162> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Method for obtaining linear spectral responsivity of InGaAs-photodetector in the NIR wavelength range

Pokatilov, Andrei; Parker, Martin; Kübarsepp, Toomas; Vabson, Viktor; Vendt, Riho; Ansko, Ilmar; Manoocheri, Farshid BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 31-34 : ill http://www.ester.ee/record=b2150914*est

Traceability of temperature measurements in Estonia

Vendt, Riho; Vabson, Viktor; **Kübarsepp, Toomas**; Noorma, Mart Proceedings of the Estonian Academy of Sciences 2013 / p. 116-121 : ill